



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

re the application of:

Gotkis et al.

Application No. 10/671,978

Filed: September 26, 2003

For: METHOD AND APPARATUS FOR WAFER
MECHANICAL STRESS MONITORING AND
WAFER THERMAL STRESS MONITORING

Group Art Unit: 2855

Examiner: DAVIS, O.

Atty. Docket No.: LAM2P438

Date: March 4, 2005

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450 on March 4, 2005.

Signed:

Melinda M. Ward

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

Dear Sir:

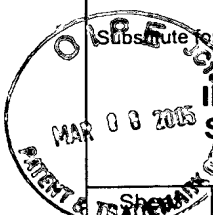
The references listed in the attached PTO Form 1449 may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§ 1.56 and 1.97. The Examiner is requested to consider these references and to acknowledge such consideration by initialing the attached PTO Form 1449 at the appropriate locations.

Applicants state that each item of information listed in the attached PTO Form 1449 was cited in a communication in a counterpart international application not more than three months prior to the filing of this statement.

Respectfully submitted,
MARTINE, PENILLA & GENCARELLA, LLP

Michael L. Gencarella, Esq.
Reg. No. 44,703

710 Lakeway Drive, Suite 200
Sunnyvale, CA 94085
Telephone: (408) 774-6921
Customer Number 25920

 Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)	1		of	1	Complete if Known	
	Application Number		10/671,978		Filing Date	
	First Named Inventor		Gotkis		Art Unit	
	Examiner Name		Davis		Attorney Docket Number	
	LAM2P438					

U.S. Patent Documents

Examiner Initials	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	B	6,477,447	Nov. 5, 2002	Lin	
	C	6,033,987	Mar 7, 2000	Tseng et al.	
	A	5,196,353	Mar 23, 1993	Doan et al.	
	D				
	E				
	F				
	G				
	H				

Foreign Patent Documents

Examiner Initial	Cite No. ¹	Foreign Patent Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number- ⁴ Kind Code ⁵ (if known)				
	I	WO 03/002301	Jan 9, 2003	Gotkis et al.		<input type="checkbox"/>
	J					<input type="checkbox"/>
	K					<input type="checkbox"/>
	L					<input type="checkbox"/>
	M					<input type="checkbox"/>

Non Patent Literature Documents

Examiner Initial	Cite No.	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published
	N	
	O	
	P	
	Q	

Examiner Signature		Date Considered	
--------------------	--	-----------------	--

Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language translation is attached.